



# ASL 1000

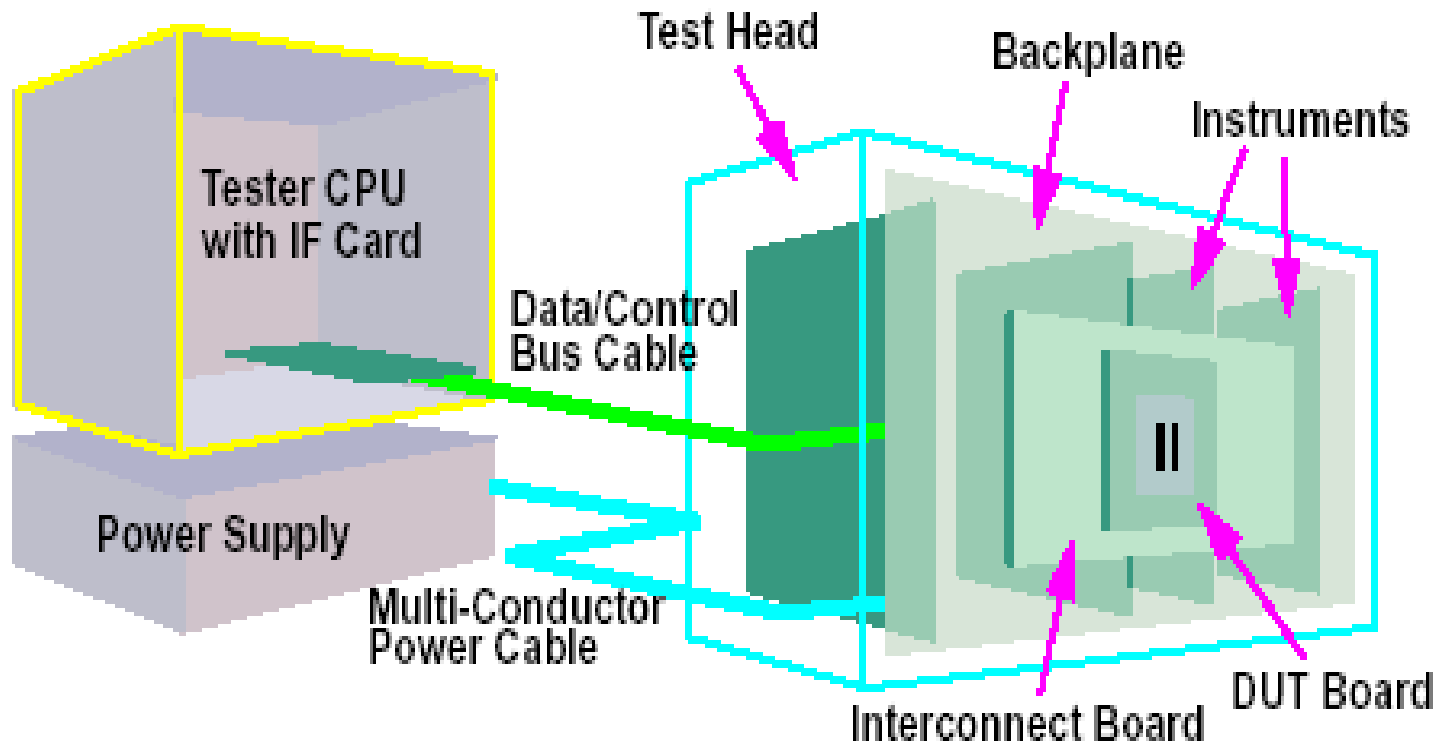
## System and Software Overview

# System Overview

- Tester CPU with test head IF board, data/control bus cable and peripherals
- Power supply  
 $\pm 5V, \pm 12V, \pm 16V, \pm 24V, \pm 50V, \pm 65V$
- Test head assembly with backplane, interconnect board and DUT board.  
MCB (1nA to 100nA)  
LCB (10pA to 1nA)
- Test instrument cards
- System Manipulator



# Hardware Architecture



# Instrument Cards

Item	Name	Instrument	Description
1	ACM	Alternating Current Multiplexer	High-speed test site for testing digital clock devices
2	ACS	Alternating Current Source	Arbitrary waveform generator and alternating current meter
3	ASB	Analog Switch Board	20-channel analog switch tester
4	DCC	Data Converter Card	Highly flexible card for testing ADCs, DACs and other converters
5	DDD	Digital Driver and Detector	8-channel digital pattern generator for digital signal stimulation and readback
6	DOAL	Dual OpAmp Loop	High-precision opamp and comparator resource for testing amplifiers in a closed loop configuration

# ASL 1000 Instrument Cards (continued)

7	DVI	Dual Voltage/Current Source	Two-channel, medium-current V/I source; provides true four-quadrant force/measure operation and rapid settling time
8	HVS	High Voltage Source	High-voltage, low-current floating source for measuring breakdown voltages, biasing or powering a device for tests by other instruments
9	LZB	Link/Zener Blower	Single quadrant V/I source optimized for link and Zener blows
10	MVS	Medium Voltage Source	Same as LZB, with medium voltage and higher current
11	MUX	Resource Multiplexer	Relay card that makes system resource or DUT connections required by a particular test application
12	OFS	Octal Floating Source	Medium-voltage, medium-current floating V/I source

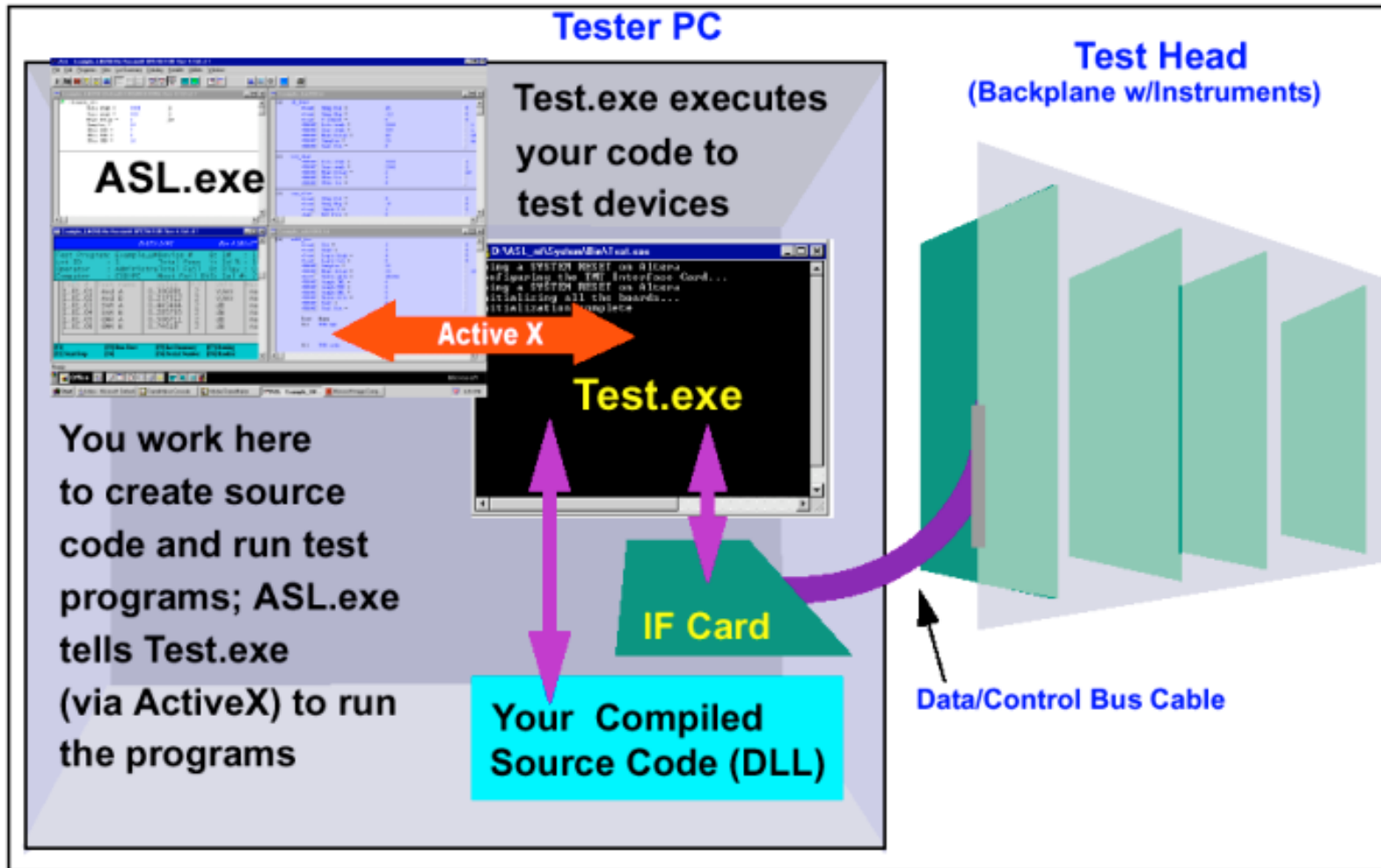
# ASL 1000 Instrument Cards (continued)

13	OVI	Octal Voltage/Current	Eight-channel, low-current V/I source that offers four-quadrant force/measure operation
14	PMU	Precision Measurement Unit	Extremely precise measuring unit that sources and measures up to 45 V and 1 A, in either single pass or dual pass mode
15	PRO	Prototyping	Configurable card used to create custom circuitry for various DUT applications
16	PVI	Pulsed V/I	Medium-voltage resource that provides a very high current, time-limited current pulse in a fully floating mode
17	RCS	Ramp Current Source	
18	TIA	Time Interval Analyzer	Two-channel, high-precision time measurement instrument mounted in the PC case
19	TMU	Time Measurement Unit	Flexible card that gives a wide range of timing measurement functions for both analog and digital devices

# ASL1000 Source

<b>Resources</b>						
<b>DC</b>	<b>Voltage</b>	<b>Current</b>	<b>Channels</b>	<b>Resolution</b>	<b>Accuracy</b>	
<b>DVI</b>	45V	2A	2	16 bits	0.03%	
<b>HVS</b>	850V	7mA	1	16 bits	0.25%	
<b>MVS</b>	100V	100mA	1	16 bits	0.20%	
<b>OFS</b>	50V	200mA	1	16 bits	0.20%	
<b>OVI</b>	16V	30mA	8	16 bits	0.10%	
<b>PVI</b>	50V	100A	1	16 bits	0.50%	
<b>AC</b>	<b>Bandwidth</b>	<b>Sample rate</b>	<b>Vrange</b>	<b>Resolution</b>	<b>Performance</b>	
<b>ACS</b>	1MHz	16MHz	10V	12 bits	2%	
<b>DIG-5</b>	5MHz	10MHz	2.5V	14 bits	70dB THD	
<b>TMU</b>	100MHz	n/a	1-1000V	<100pS	10nS	
<b>Digital</b>	<b>Frequency</b>	<b>Channels</b>	<b>Levels</b>	<b>Resolution</b>	<b>Performance</b>	
<b>DDD</b>	14MHz	8	"-5V to + 15V"	100pS	3nS	
<b>TIA</b>	400MHz	2	"-5V to + 15V"	75pS	0.5nS	
<b>Application</b>	<b>Description of application specific resource</b>					
<b>DOAL</b>	Two OP-AMP loops, pole/zero compensation, VIO range=100uV, AVOL >120dB					
<b>LCB</b>	8 pico ammeters, 100pA full scale range, measure 1pA					
<b>DCC</b>	ADC / DAC high speed servo loop, 0.5mS code measure, 20 bit reference, 16 I/O					
<b>LZB</b>	Zener link trim card, 40V, 700mA continuous, 4A pulsed, 2x28 matrix					

# Visual ATE Architecture





# Visual ATE Architecture

Executable Files:

## **Init.exe**

- 1.Run on system startup and on Visual ATE startup.
- 2.Initialize the ASL test head interface card and the test instruments.

## **ASL.exe**

- 1.Let user Analyze and manipulate data, communicate instructions to the tester control program.
- 2.Communicate user action to the hardware control.
- 3.Create source files for the system compiler(Visual C++).
- 4.Create Visual C++ project files(\*.dsp),complete header files(\*.h), and source code files(\*.cpp).

# Visual ATE Architecture

Executable Files(continued):

## **Test.exe**

1. Control the test head instrumentation during component testing as well as data collection.
2. Link to the compiled code(DLL) and direct the tester hardware to test devices according to the test program instructions.
3. Use the Visual ATE system DLLs to control instrument calibration and system events.

## **HandlerMgr.exe**

Allowing user to create and manage interface card-based handlers.

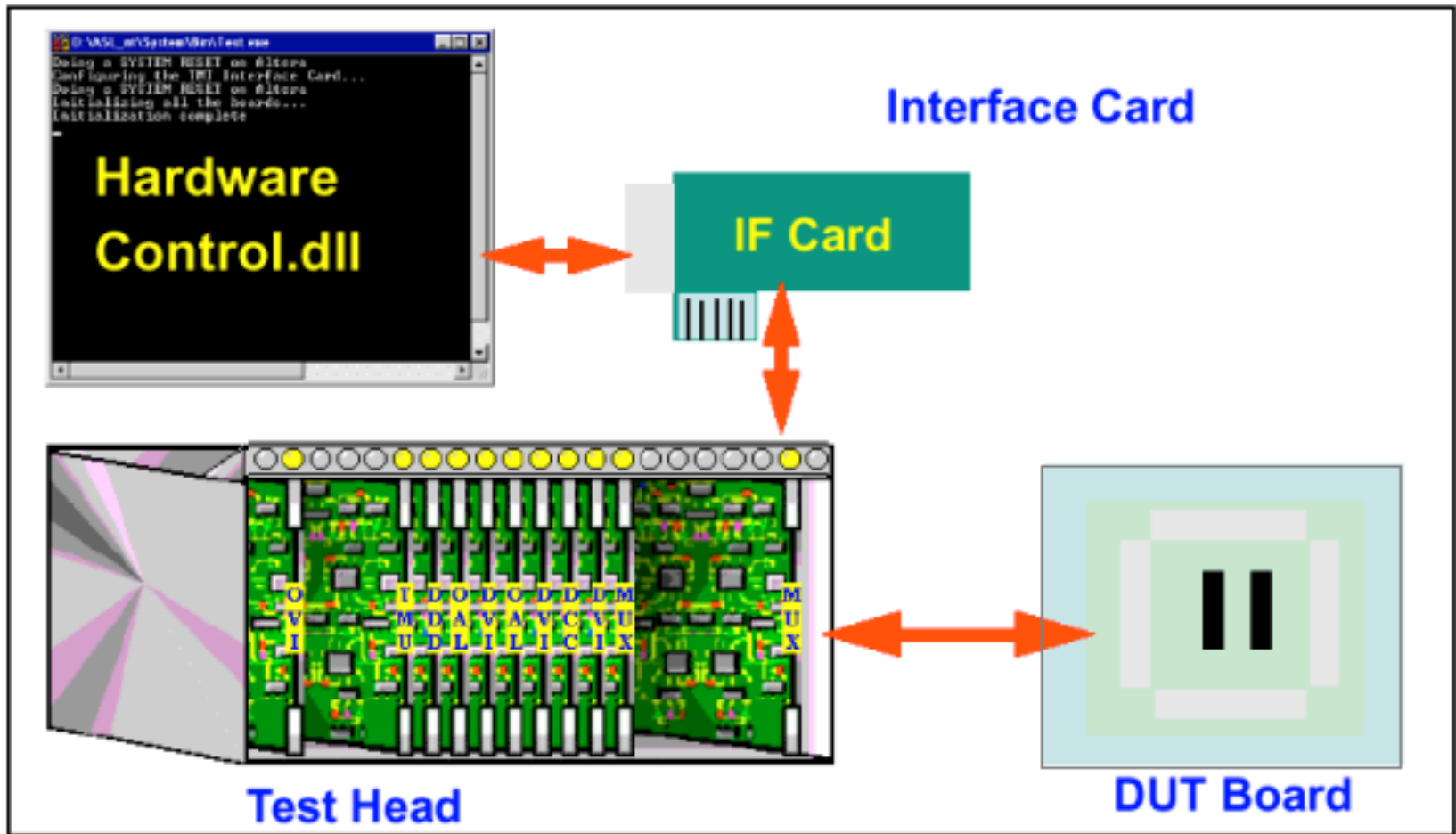
# Visual ATE Architecture

## Dynamic Link Library Files (\*.DLL)

Windows library of routines and resources that links to the \*.exe files at run time.

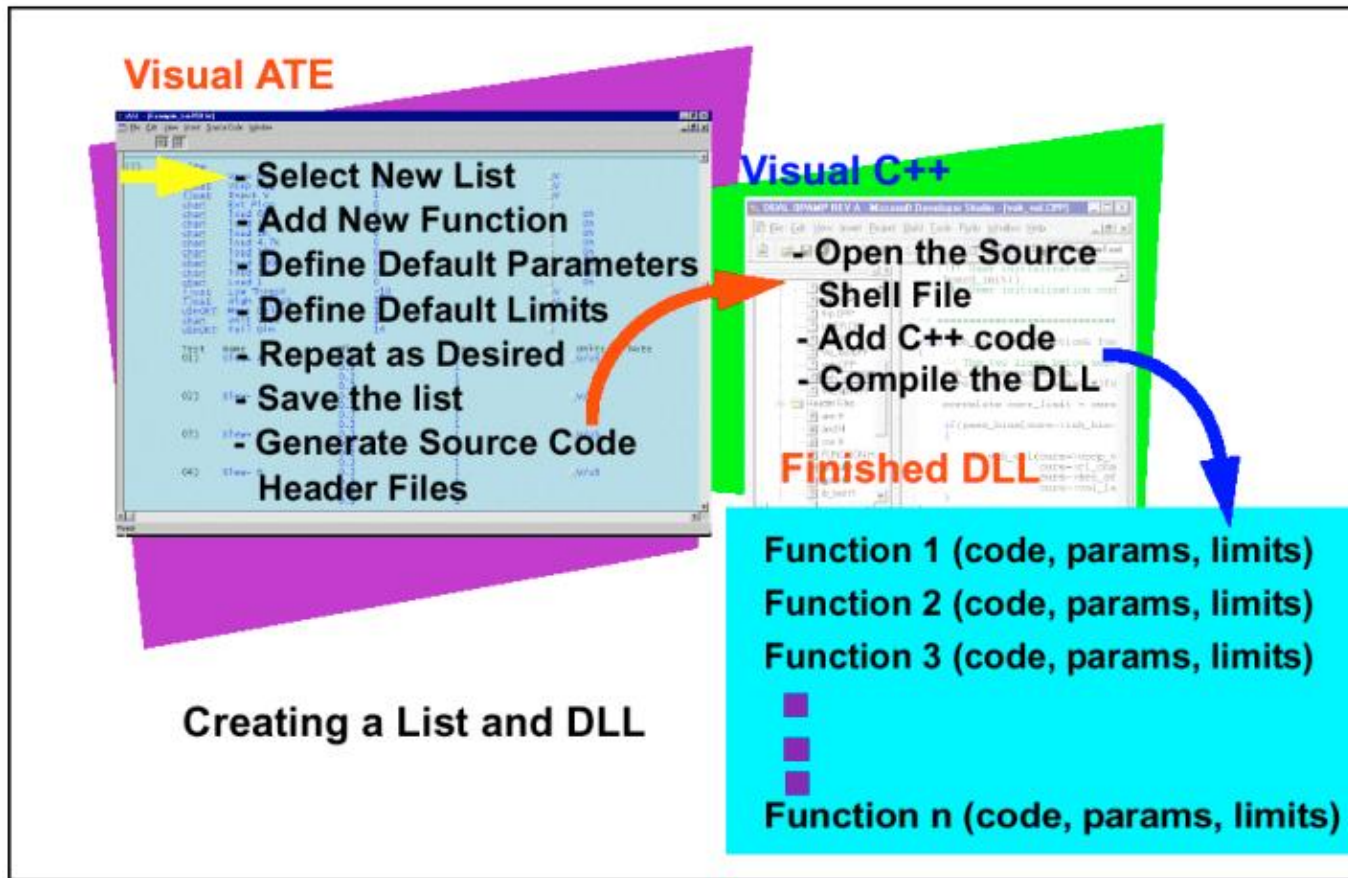
All user-written code is compiled into DLLs, Visual ATE has its own system DLLs with hardware and interface controls.

# Visual ATE Test Structure



# Visual ATE Test Structure

## Lists and Source Code Files



# Visual ATE Test Structure

## Test Programs

**Compiled DLL**

- Function1 (code, params, limits)
- Function2 (code, params, limits)
- Function3 (code, params, limits)
- Function4 (code, params, limits)
- Function5 (code, params, limits)

**Visual ATE**

**Creating a Test Program**

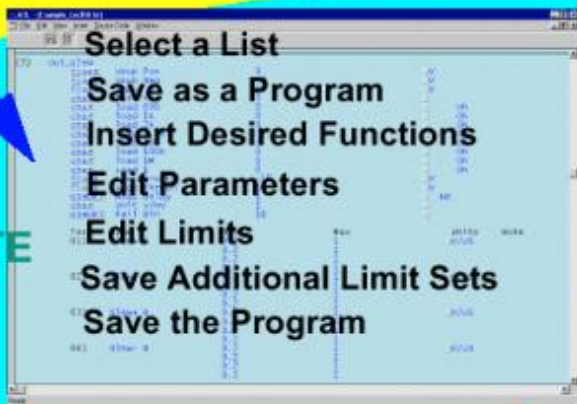
**Test Programs**

**Same Program, Different Limit Sets**

- Execute Function3 with Final Limits
- Execute Function2 with Final Limits
- Execute Function5 with Final Limits
- Stop, change limits, then run again

**Different Program**

- Execute Function1 with Test Limits
- Execute Function4 with Test Limits
- Execute Function3 with Test Limits
- Execute Function5 with Test Limits



# File Types

File Type	Extension	Description
Datalog	*.dl4	Standard Visual ATE database format
Datalog	*.stdf	Standard test database file format
Dynamically Linked Library	*.dll	A shared object library; compiled test functions that are loaded at run time.
Handler Data	*.pin	Generated by the Handler Manager, has handler data
List	*.lst	Generated in Create, these files are the basis for generating DLLs.
Lot summary	*.ls4	Binary file, bin data output summary generated from Lot Summary
Lot summary	*.lsr	ASCII file, bin data output summary generated from Lot Summary
NT Export	*.nx4	Generated by the export command in Create mode
Spreadsheet	*.spd	Comma-delineated text file compatible with most spreadsheet programs
Test Program	*.prg	Generated by actions while in Engineering mode

# File Types (continued)

File Type	Extension	Description
Text	*.txt	ASCII text that can be manipulated as follows: Report: — Optional output from Engineering or Create Spreadsheet: — Datalog files from Datalog screen Text: — Output from Datalog screen



# Visual ATE User Interface

## Visual ATE Operating Modes

### Operator

Running test programs

Saving and printing test data

Checking instruments.

### Engineering

Writing and running test programs

An editor for writing test programs

A run screen for collecting test data.

(cont.)

# Visual ATE User Interface

## Visual ATE Operating Modes (cont.)

### Create

Construct list files(later compiled into DLLs)

Generate source code

Access all VisATE file types

### System Administrator

Define the VisATE system properties and use system utilities

### Maintenance

Calibrate and verify the installed test instruments

(END)